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2.1			Grav. P.R. et al	P.R. et al., Analysis And Design Of Analog Integrated Circuits, Fourth Edition, John Wiley & Sons, Inc., pp. ix-xviii, 217-232 and 253-					
PN	AR	<u>1</u>	336 (2001).						
PN			IEEE Std 1596.3-1996 - Description, from http://standards.iee.org/reading/ieee/std_public/description/busarch/1596.3-1996_desc.html, 2 Pages (last update: March 31, 1999).						
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